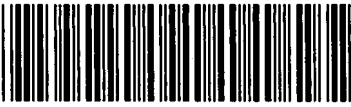


<b>Search Notes</b>  	<b>Application/Control No.</b>  10526660	<b>Applicant(s)/Patent Under Reexamination</b>  TANAKA ET AL.
	<b>Examiner</b>  Cho, Jennifer Y	<b>Art Unit</b>  1621

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
East Search	8/28/07	JC
STIC Search	8/10/07	HM
STN Search	8/28/07	JC
STN Search	8/28/07	SB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
East Text Search of 560/61 and 514/543		8/29/07	JC